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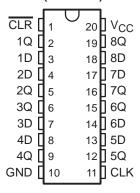
- State-of-the-Art EPIC-IIB™ BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17
- Typical V_{OLP} (Output Ground Bounce) < 1 V at V_{CC} = 5 V, T_A = 25°C
- High-Drive Outputs (–32-mA I_{OH}, 64-mA I_{OL})
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), Plastic (N) and Ceramic (J) DIPs, and Ceramic Flat (W) Package

description

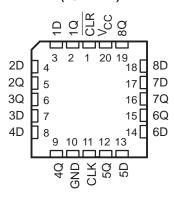
The 'ABT273 are 8-bit positive-edge-triggered D-type flip-flops with a direct clear (CLR) input. They are particularly suitable for implementing buffer and storage registers, shift registers, and pattern generators.

Information at the data (D) inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a particular voltage level and is not directly related to the transition time of the positive-going pulse. When the clock (CLK) input is at either the high or low level, the D input signal has no effect at the output.

SN54ABT273 . . . J OR W PACKAGE SN74ABT273 . . . DB, DW, N, OR PW PACKAGE (TOP VIEW)



SN54ABT273 . . . FK PACKAGE (TOP VIEW)



The SN54ABT273 is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74ABT273 is characterized for operation from -40° C to 85° C.

FUNCTION TABLE (each flip-flop)

	INPUTS	OUTPUT	
CLR	CLK	D	Q
L	Х	Χ	L
Н	\uparrow	Н	н
Н	\uparrow	L	L
Н	H or L	Χ	Q ₀



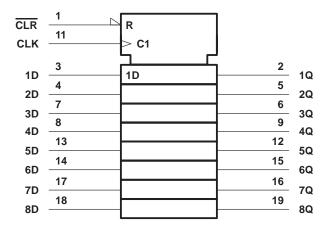
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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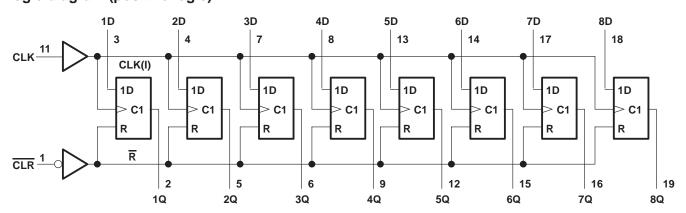
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logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V _{CC}		–0.5 V to 7 V
Input voltage range, V _I (see Note 1)		–0.5 V to 7 V
Voltage range applied to any output in the high	or power-off state, V _O	. −0.5 V to 5.5 V
Current into any output in the low state, Io: SN	154ABT273	96 mA
SN	174ABT273	128 mA
Input clamp current, I _{IK} (V _I < 0)		–18 mA
Output clamp current, I _{OK} (V _O < 0)		–50 mA
Package thermal impedance, θ_{JA} (see Note 2):	DB package	115°C/W
	DW package	97°C/W
	N package	67°C/W
	PW package	128°C/W
Storage temperature range, T _{stg}		–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

^{2.} The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51, except for through-hole packages, which use a trace length of zero.



NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

recommended operating conditions (see Note 3)

		SN54ABT273		SN74ABT273		UNIT
		MIN	MAX	MIN	MAX	UNIT
Vcc	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2		2		V
VIL	Low-level input voltage		0.8		0.8	V
VI	Input voltage	0	VCC	0	VCC	V
IOH	High-level output current		-24		-32	mA
lOL	Low-level output current		48		64	mA
Δt/Δν	Input transition rise or fall rate		10		10	ns/V
TA	Operating free-air temperature	- 55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS			1	T _A = 25°(0	SN54A	BT273	SN74A	UNIT	
PARAMETER				MIN	TYP [†]	MAX	MIN	MAX	MIN	MAX	ONIT
VIK	$V_{CC} = 4.5 \text{ V},$	$I_{I} = -18 \text{ mA}$				-1.2		-1.2		-1.2	V
	$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -3 \text{ mA}$		2.5			2.5		2.5		
Vou	$V_{CC} = 5 V$,	$I_{OH} = -3 \text{ mA}$		3			3		3] , [
VOH	V _{CC} = 4.5 V	I _{OH} = -24 mA		2			2				V
	vCC = 4.5 v	$I_{OH} = -32 \text{ mA}$		2*					2		
Voi	V _{CC} = 4.5 V	$I_{OL} = 48 \text{ mA}$				0.55		0.55			V
VOL	VCC = 4.5 V	$I_{OL} = 64 \text{ mA}$				0.55*				0.55	
V _{hys}					100						mV
lį	$V_{CC} = 5.5 \text{ V},$	$V_I = V_{CC}$ or GN	ND			±1		±1		±1	μΑ
l _{off}	$V_{CC} = 0$,	V_I or $V_O \le 4.5$	V			±100				±100	μΑ
ICEX	$V_{CC} = 5.5 \text{ V},$	V _O = 5.5 V	Outputs high			50		50		50	μΑ
I _O ‡	$V_{CC} = 5.5 \text{ V},$	V _O = 2.5 V		-50	-100	-200§	-50	-200§	-50	-200§	mA
	V _{CC} = 5.5 V, I _O	CC = 5.5 V, IO = 0,	Outputs high		1	400§		400§		400§	μΑ
	$V_I = V_{CC}$ or GND Outputs low		Outputs low		24	30		30		30	mA
ΔICC¶	V _{CC} = 5.5 V, Or Other inputs at V	ne input at 3.4 V, V _{CC} or GND				1.5		1.5		1.5	mA
Ci	V _I = 2.5 V or 0.5	5 V	·		7						pF

^{*} On products compliant to MIL-PRF-38535, this parameter does not apply.



[†] All typical values are at $V_{CC} = 5 \text{ V}$.

[‡] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

[§] This data sheet limit may vary among suppliers.

[¶] This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

SN54ABT273, SN74ABT273 OCTAL EDGE-TRIGGERED D-TYPE FLIP-FLOPS WITH CLEAR

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timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

			V _{CC} = 5 V, T _A = 25°C		SN54ABT273		SN74ABT273		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	
fclock	Clock frequency		0	150	0	150	0	150	MHz
A Dulas	Pulse duration	CLK high or low	3.3		3.3		3.3		ns
t _W	ruise duration	CLR low	3.3		3.3		3.3		
		Data high	2		2		2		
t _{SU} Setup time b	Setup time before CLK↑	Data low	2.5		2.5		2.5		ns
		CLR high	2		2		2		
t _h	Hold time after CLK↑	Data high or low	1.2†		1.4†		1.2†		ns

[†] This data sheet limit may vary among suppliers.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50$ pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} =	= 5 V, 25°C	SN54A	UNIT	
	(1141 01)	(0011 01)	MIN	MAX	MIN	MAX	
fmax			150		150		MHz
^t PLH	CLIK	Q	2.5	6	2.5	7	ne
t _{PHL}	CLK		3.3	6.8	3.3	7.5	ns
^t PHL	CLR	Q	2.5	7.5†	2.5	8.2	ns

[†] This data sheet limit may vary among suppliers.

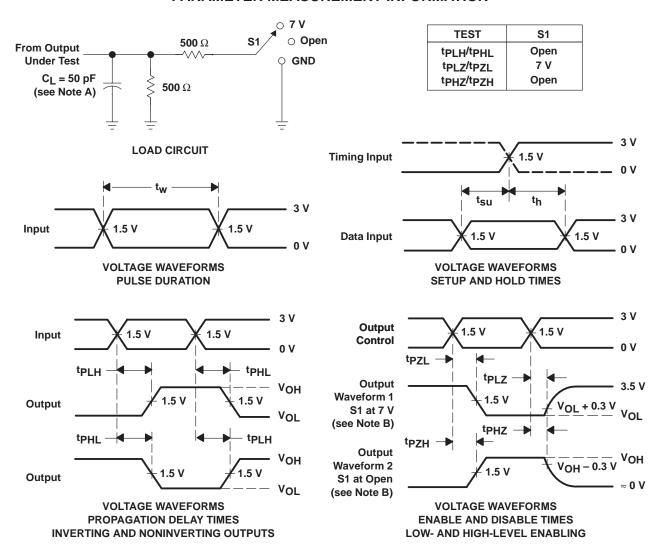
switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50$ pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 5 V, T _A = 25°C		SN74ABT273		UNIT
	(INFOT) (OUTFOT)	MIN	MAX	MIN	MAX		
f _{max}			150		150		MHz
t _{PLH}	CLK	Q	2.5	6	2.5	6.5	ns
t _{PHL}	CLK	ų ,	3.3	6.8	3.3	7.3	115
t _{PHL}	CLR	Q	2.5	6.7†	2.5	7.4†	ns

[†] This data sheet limit may vary among suppliers.



PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50~\Omega$, $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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